

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Changes in table I. Change CAGE code identification number to 67268.	1987 AUG 3	M. A. Frye
B	Add case outline 2. Editorial changes throughout.	1990 JUNE 4	M. A. Frye

CURRENT CAGE CODE 67268

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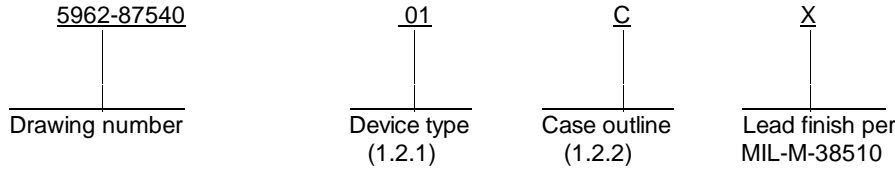
REV STATUS OF SHEETS	REV	B	B	B	B	B	B	B	B	B	B								
	SHEET	1	2	3	4	5	6	7	8	9									

PMIC N/A	PREPARED BY Joseph A. Kerby	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444																		
STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	CHECKED BY Charles E. Besore																			
	APPROVED BY Michael A. Frye	MICROCIRCUITS, LINEAR, HIGH SPEED, SAMPLE-AND-HOLD AMPLIFIER, MONOLITHIC SILICON																		
	DRAWING APPROVAL DATE 16 April 1987																			
	REVISION LEVEL B																			
		SIZE A	CAGE CODE 14933	5962-87540																
	SHEET 1 OF 9																			

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	AD585	High speed, sample-and-hold amplifier

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

<u>Outline letter</u>	<u>Case outline</u>
C	D-1 (14-lead, .785" x .310" x .200"), dual-in-line package
2	C-2 (20-terminal, .358" x .358" x .100"), chip carrier package

1.3 Absolute maximum ratings. 1/

Supplies (+V _S , -V _S)	±18 V dc
Logic inputs	±V _S
Analog inputs	±V _S
R _{IN} , R _{FB} pins	±V _S
Output short circuit to ground	Indefinite
TTL logic reference short circuit to ground	Indefinite
Storage temperature range	-65° C to +150° C
Lead temperature (soldering, 10 seconds)	+300° C
Thermal resistance:	
Junction to case (Θ _{JC})	See MIL-M-38510, appendix C
Junction to ambient (Θ _{JA})	110° C/W

1.4 Recommended operating conditions.

Supply voltage range:	
+V _S	+5 V dc to +18 V dc
-V _S	-12 V dc to -18 V dc
Ambient operating temperature range (T _A)	-55° C to +125° C

1/ Unless otherwise specified, all voltages are referenced to ground.

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Functional block diagram. The functional block diagram shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Offset voltage	V _{OS}	V _{OUT} = 0 V	1, 2, 3	-3	+3	mV
			4	-2	+2	
Bias current	I _B	V _{IN} = 0 V	1	-2	+2	nA
Bias current over temperature	I _B ΔT		2	-50	+50	
TTL reference output	V _{LREF}	50 μA load	1	1.2	1.6	V
TTL reference output over temperature	V _{LREF} ΔT		2, 3	0.8	1.9	
Logic input high voltage	V _{IH}	Hold = V _{LREF}	1	2.0		V
Logic input high voltage over temperature	V _{IH} ΔT	Hold = V _{LREF}	2, 3	2.0		
Logic input low voltage	V _{IL}	Hold = V _{LREF}	1		0.8	
Logic input low voltage over temperature <u>2/</u>	V _{IL} ΔT	Hold = V _{LREF}	2, 3		0.7	
Logic input current	I _{IL}	V _S = ±18 V	1, 2, 3		50	μA
Supply current	I _{SS}	R _L = Infinite	1, 2, 3		10	mA
Power supply rejection	PSRR	+V _S = +5 V to +18 V -V _S = -12 V to -18 V V _{IN} = V _{OUT} = 0 V T _A = +25°C	1	70		dB
Acquisition time	t _{acq}	10 V step to 0.01% T _A = +25°C	7		3	μs
		20 V step to 0.01% <u>3/</u> T _A = +25°C			5	
Droop rate <u>2/ 4/</u>	V _{DRP}	V _{IN} = 0 V T _A = +25°C	4		1	mV/ms

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Sample-to-hold offset <u>2/</u>	SH _{OS}	V _{IN} = 0 V T _A = +25°C	4		3	mV
Application resistor mismatch	ΔRM		1, 2, 3		0.3	%
Common mode rejection	CMRR	V _{CM} = ±10 V	1	80		dB
Common mode rejection over temperature	CMRRΔT	V _{CM} = ±10 V	2, 3	77		
Slew current <u>5/</u>	I _{SL}		4	850		μA
Slew current over <u>5/</u> temperature	I _{SL} ΔT		2, 3	600		
Output resistance	R _{OUT}	I _{OUT} = ±10 mA	1		0.05	Ω
Output resistance over temperature	R _{OUT} ΔT	I _{OUT} = ±10 mA	2, 3		0.10	
Output current	I _{OUT}	R _L = 100Ω, T _A = +25°C	1	12		mA

1/ V_S = ±15 V, C_H = Internal, R_L = Infinite, A = +1, Ho I d active, sample mode unless otherwise noted.

2/ Tested in hold mode.

3/ Guaranteed if not tested to the limits specified.

4/ Doubles every 10°C.

5/ V_{OUT} = 20 Vp-p. Slew rate = slew current/C_H.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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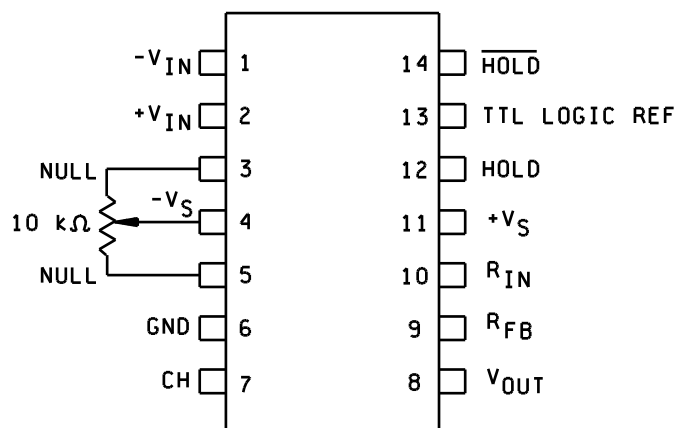
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Case outline C



Case outline 2

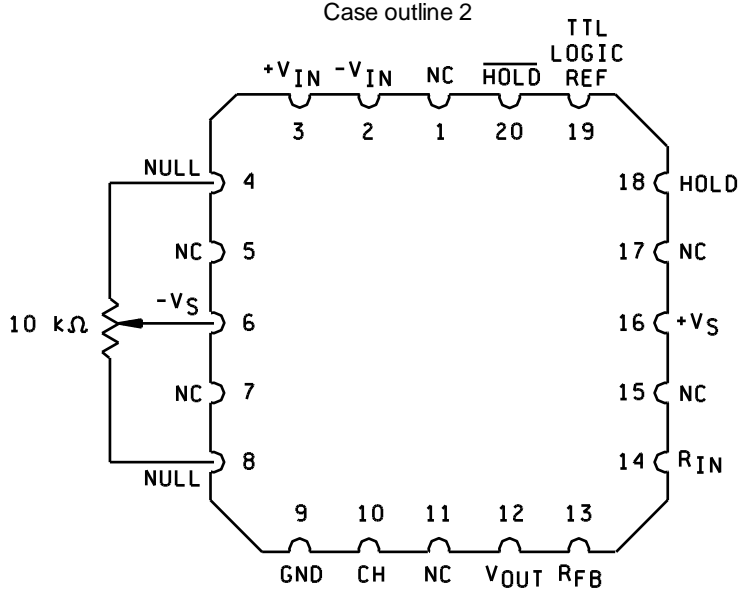


FIGURE 1. Terminal connections.

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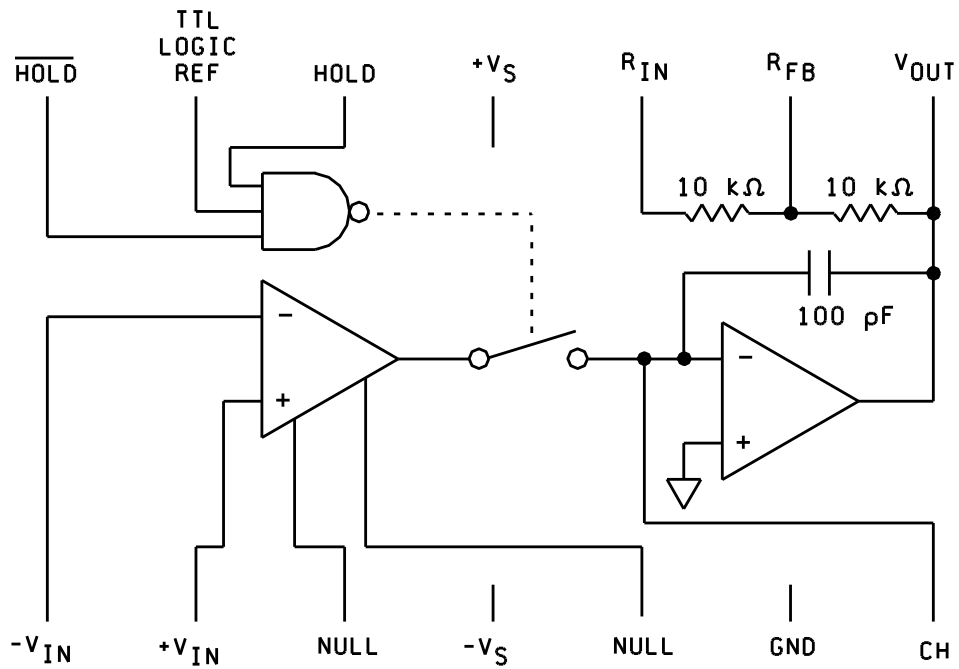


FIGURE 2. Functional block diagram.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5, 6, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 4
Group A test requirements (method 5005)	1, 2, 3, 4, 7
Groups C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

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5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.

6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved sources listed below are for information purposes only and are current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number ^{1/}
5962-8754001CX	24355	AD585SQ/883B
5962-87540012X	24355	AD585SE/883B

^{1/} Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

24355

Vendor name and address

Analog Devices
 RT 1 Industrial Park
 P.O. Box 9106
 Norwood, MA 02062
 Point of contact: 804 Woburn Street
 Wilmington, MA 01887

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